

OP 3642
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PATENT
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Martin Fuchs et al. Art Unit: 3642
Serial No.: 09/087,141 Examiner:
Filed : May 28, 1998
Title : METHOD AND DEVICE FOR MEASURING THIN FILMS AND
SEMICONDUCTOR SUBSTRATES

Assistant Commissioner for Patents
Washington, DC 20231

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached
form PTO 1449, copies of which are enclosed.

This statement is being filed before the receipt of a
first Office action on the merits. Please apply any charges or
credits to Deposit Account 06-1050.

Respectfully submitted,

Date: November 5, 1998

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Date of Deposit November 5, 1998
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